

Special Issue

New Insights into Digital Image Processing and Denoising

Message from the Guest Editors

Nowadays, in the era of cutting-edge technologies, the implementation of digital image processing techniques has become a key element of many solutions. This is because there are several potential innovative digital imaging applications that include different areas such as geographic information systems (GIS), environmental and traffic monitoring, quality control in production automation, medical diagnosis and treatment, autonomous vehicles, defense vision, robotics, remote sensing, art and cultural heritage preservation and exploitation, detecting crime and threats, 3D modeling and multimedia, etc. The growing trends and requirements of the above-mentioned image applications are an increasing challenge for researchers and engineers dealing with digital image processing (DIP). Therefore, DIP is a multidisciplinary science that employs knowledge from various fields such as computer science, mathematics, and also visual psychophysics. The aim of this Special Issue is to bring together high-quality scientific papers and reports from a wide range of specialists that could provide comprehensive insights into modern approaches of digital image processing and denoising.

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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